SDLS082

DECEMBER 1983-REVISED MARCH 1988

- Package Options Include Plastic and Ceramic DIPs and Ceramic Flat Packages
- Dependable Texas Instruments Quality and Reliability

description

These devices contain dual 4-input positive NOR gates with strobe. They perform the Boolean function:

$$Y = \overline{G(A+B+C+D)}$$
(with 1X and $\overline{1X}$ of '23 left open).

The SN5423 and the SN5425 are characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 °C. The SN7423 and the SN7425 are characterized for operation from 0 °C to 70 °C.

FUNCTION TABLE

	I	NPU1	OUTPUT		
Α	В	C	D	G	Υ
Н	х	Х	X	н	L
Х	Н	×	Х	Н	L
X	X	Н	X	Н	L
Х	X	X	H	Н	
L	L	L	L	Х	Н
X	х	х	X	L	н

Expander inputs are open,
H = high level, L = low level, X = irrelevant

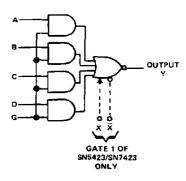
SN5423 . . . J OR W PACKAGE SN7423 . . . N PACKAGE (TOP VIEW) 1X 1 16 VCC 1A 2 15 1X

1X 🛚	1	U_{16}	∐ V <u>c</u> c
1A 🛚	2	15] 1X
1B 🛚	3	14:] 2D
1G 🗌	4	13] 2C
1C 🛚	5	12] 2G
1D 🛚	6	11] 2B
17 🛚	7	10] 2A
GND 🗍	8	9] 2Y

SN5425 . . . J OR W PACKAGE SN7425 . . . N PACKAGE

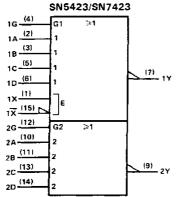
GND [

logic diagram



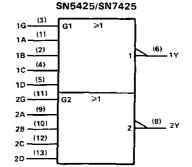
8 2Y

logic symbols†



[†]These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers are for J, N, or W packages.

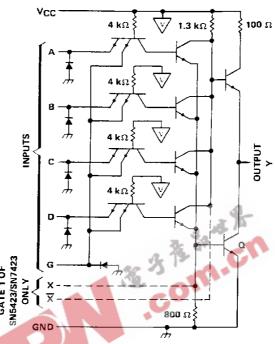
TEXAS VINSTRUMENTS



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SN5423, SN5425, SN7423, SNSN7425 **DUAL 4-INPUT NOR GATES WITH STROBE**

schematic (each gate)



- NOTES: A. Component values shown are nominal
 - B. Both expander inputs are used simultaneously for expanding.
 C. If expander is not used leave X and X open.

 - D. A total of four expander gates can be connected to the expander inputs.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage VCC (see Note 1)	, 7 V
Input voltage (see Note 1)	5.5 V
Interemitter voltage (see Note 2)	
Operating free-air temperature range: SN5423, SN5425 Circuits	
SN7423, SN7425 Circuits	
Storage temperature range	

- NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.
 - 2. This is the voltage between two emitters of a multiple-emitter transistor.

recommended operating conditions

			'23 , '25			UNIT	
			MIN	NOM	MAX	OMIT	
		54 Family	4.5	5	5.5	v	
vcc	Supply voltage	74 Family	4.75	5	5.25		
VIH	High-level input voltage		2			V	
VIL	Low-level input voltage				0.8	٧	
Іон	High-level output current				- 0.8	mA	
		54 Family			16	mΑ	
OF	Low-level output current	74 Family			16		
_		54 Family	- 55		125	°c	
T_A	Operating free-air temperature range	74 Family	0	•	70		

The '23 is designed for use with up to four '60 expanders.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAF	RAMETER		TEST CON	IDITIONS		MIN	TYP‡	MAX	UNIT	
Vı		V _{CC} = MIN,	lį = — 12 mA					– 1.5	V	
Voн		VCC = MIN,	V _{IL} = 0.8 V,	I _{OH} = - 0.8 mA		2.4	3.4		٧	
VOL		V _{CC} = MIN,	V _{IH} = 2 V,	I _{OL} = 16 mA			0.2	0.4	٧	
l _l		V _{CC} = MAX,	V ₁ = 5.5 V					1	mΑ	
	data inputs		. V ₁ = 2.4 V					40) μΑ	
³1H	strobe inputs	V _{CC} = MAX,	V - 2.4 V					160		
	data inputs	V MAY	V ₁ = 0.4 V					1.6	mΑ	
ЧL	strobe inputs	VCC - MAX,				- 6.4				
		\/ MAY			54 Family	- 20		- 55		
loss		V _{CC} = MAX			74 Family	– 18		- 55	mA	
1ссн		V _{CC} = MAX,	All inputs at 0 \	V			8	16	mΑ	
ICCL		V _{CC} = MAX,	All inputs at 5 \	/	-G		10	19	mΑ	

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type. Expander inputs X and \overline{X} are open.

electrical characteristics (SN5423 circuits) using expander inputs, VCC = 4.5 V, TA = -55°C

	PARAMETER	TEST	CONDITIONS		MIN	TYP	MAX	UNIT
١x̄	Expander current	V _X X = 0.4 V,	I _{OL} = 16 mA				- 3.5	mΑ
VBE(Q)	Base-Emitter voltage of output transistor (Q)	IOL = 16 mA,	$I_X + I_X^{-2} = 0.41 \text{ mA},$	$R_{X}\overline{X} = 0$			1.1	٧
Voн	High-level output voltage	$I_{OH} = -0.4 \text{mA},$	I _X = 0.15 mA,	$I\overline{\chi} = -0.15 \text{ mA}$	2.4	3.4		٧
VOL	Low-level output voltage	IOL = 16 mA,	$I_X + I_{\overline{X}} = 0.3 \text{ mA},$	$R_{X\bar{X}} = 114 \Omega$		0.2	0.4	V

electrical characteristics (SN7423 circuits) using expander inputs, VCC = 4.75 V, TA = 0°C

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
ίχ	Expander current	V _X \overline{\times} = 0.4 V ,	I _{OL} = 16 mA				- 3.8	mA
VBE(Q)	Base-Emitter voltage of output transistor (Q)	I _{OL} = 16 mA,	$I_X + I_{\overline{X}} = 0.62 \text{ mA},$	H _X X = 0			1	٧
Voн	High-level output voltage	I _{OH} = - 0.4 mA,	I _X = 0.27 mA,	1 √ = → 0.27 mA	2.4	3.4		V
VOL	Low-level output voltage	IOL= 16 mA,	$1_{X} + 1_{X}^{-} = 0.43 \text{ mA},$	$H_{XX} = 130 \Omega$		0.2	0.4	V

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$, N = 10, (see note 3)

PARAMETER	TEST CON	MIN	TYP	MAX	UNIT	
tPLH	R _L = 400 Ω,	C _L = 15 pF		13	22	ns
tPHL .	R _L = 400 Ω,	C _L = 15 pF		8	15	ns

NOTE 3: Switching characteristics of the SN5423 and SN7424 are tested with the expander pins open.

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{ C}$. § Not more than one output should be shorted at a time.

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